Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination	
10708730	HO ET AL.	
Examiner	Art Unit	
Detschel, Marissa J	2877	

SEARCHED						
Class	Subclass	Date	Examiner			
356	328, 334	12/8/06	MJD			

SEARCH NOTES				
Search Notes	Date	Examiner		
Updated EAST search from 5/5/06	12/8/06	MJD		
Consulted Fannie Evans on allowable subject matter	1/11/07	MJD		
Search terms: curved, concave, grating, path difference, arc length, groove, distance, position, slit, detector	1/4/07	MJD		

INTERFERENCE SEARCH						
Class	Subclass	Date	Examiner			

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